IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Jean-Pierre KLEIN

Conf.

Application No. NEW NATIONAL PHASE

Group

Filed June 2, 2006

Examiner

DEVICE FOR THE EARTHQUAKE-RESISTANT MOUNTING OF A PARTITION

INFORMATION DISCLOSURE STATEMENT (SUBMISSION CONCURRENT WITH THE FILING OF A NEW PATENT APPLICATION)

Assistant Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

June 2, 2006

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, and in fulfillment of the duty of disclosure under 37 C.F.R. § 1.56, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

I. LIST OF PATENTS, PUBLICATIONS OR OTHER INFORMATION

The patents, publications, or other information submitted for consideration by the Office are listed on PTO-1449, attached hereto.

II. COPIES

Copies	of	the	U.S.	patents	or pu	blications	are	not	submitted
 since	the	USPT	O has	waived	their	submission	ı for	app	olications
filed	afte.	r Jur	ne 30,	2003.					

- Submitted herewith is a legible copy of (i) each foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
- This application is a National Phase of a PCT application. Some or all of the documents listed on the PTO-1449 are not enclosed because they were cited in the International Search Report and copies should have been forwarded from the International Search Authority pursuant to the trilateral agreement between the USPTO, EPO and JPO, or they are U.S. patents or U.S. published applications. If copies are needed, please contact the undersigned.

Docket No. 0598-1010 III. CONCISE EXPLANATION OF THE RELEVANCE AP20 Rec'd PCT/PTO 02 JUN 2006 (check at least one box) DOCUMENTS IN THE ENGLISH LANGUAGE a. The attached non U.S. patents, non U.S. patent application publications, foreign publications, or other information in the English language do not require a statement of relevancy. DOCUMENTS NOT IN THE ENGLISH LANGUAGE b. П A concise explanation of the relevance of all patents, publications, or other information listed that is not in the English language is as follows: FOREIGN SEARCH REPORT OR ACTION \boxtimes c. An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby satisfying the requirement explanation. See MPEP 609(A)(3). for concise OTHER d. The following additional information is provided for the Examiner's consideration. FEES Information Disclosure Statement is being concurrently with the filing of a new patent application; therefore, no fee is required. If The Examiner has any questions concerning this IDS, he/she is requested to contact the undersigned. Respectfully submitted, YOUNG & THOMPSON Il Castel Benoit Castel, Reg. No. 35,041 745 South 23rd Street Arlington, VA 22202 Telephone (703) 521-2297 Telefax (703) 685-0573 (703) 979-4709

 \boxtimes Form PTO-1449(s) Enclosures: 冈 Documents Foreign Search Report 冈 Other:____

IAP20 Rec'd PCT/PTQ viz JUN 2006 Sheet 1 of 1

INFO	DRMATION DISCLOSUR	E CITATION	0598-1010	Application No.: NEW NATIONAL PHASE 1 0 / 5 8 1 3 4 1 Group Art Unit:					
	IN AN APPLICATION	ON	Applicant: Jean-Pierre KLEIN						
	(Use several sheets if neces	ssary)	Filing Date: June 2, 2006						
		U.S. PATEN	IT DOCUMENTS						
Examine Initial	Document Number	Date	Name	Class	Subclass	Filing date (if appropriate)			
				-	<u> </u>				
				-					
				-					
					_				
			-	_		<u> </u>			
						ļ			
							 		
		FOREIGN PA	TENT DOCUMENTS	<u> </u>	l				
Examiner	Document Number	Date	Country	Cla	ass Subclas	s Tran	Translation		
Initial	00.00.400	2/28/1980	GERMANY		-	Yes No			
	28 36 126	2/20/1900	GERIVIAINT						
									
	OTHER DOCUME	EN IS (Including A	Author, Title, Date, Pertin	ent Page	es, etc.)				
			<u> </u>	· · · · · · · · ·					
EVAN	NED:		DATE CONSIDERED						
EXAMI	NEK:		DATE CONSIDERED						
EXAMIN not in co	IER: Initial if citation considered, informance and not considered. It	whether or not citation	on is in conformance with MPI	EP § 609. to the app	Draw line thr	ough citat	ion if		

* English language abstract provided for the Examiner's convenience

ldw